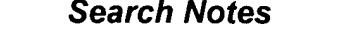


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/032,729	CHEN ET AL.
	Examiner	Art Unit
	John L. Shew	2664

SEARCHED			
Class	Subclass	Date	Examiner
370	347,352	11/28/2005	JS
	363,367		
	368,371		
	378,379		
	381,389		
	390		
	395.3		
	412,428		
	429		
708	232,273	11/28/2005	JS
709	230,236	11/28/2005	JS
	238,243		
	250		
710	310	11/28/2005	JS